

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination SHERLOCK ET AL.	
		Examiner Tadesse Hailu	Art Unit 2173	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,463,470	10-2002	Mohaban et al.	709/223
*	B	US-6,279,037	08-2001	Tams et al.	709/224
*	C	US-6,505,245	01-2003	North et al.	709/223
*	D	US-6,792,458	09-2004	Muret et al.	709/224
*	E	US-6,484,143	11-2002	Swildens et al.	705/1
*	F	US-6,453,345	09-2002	Trcka et al.	709/224
*	G	US-6,269,447	07-2001	Maloney et al.	726/25
*	H	US-6,901,442	05-2005	Schwaller et al.	709/224
*	I	US-2005/0195964	09-2005	Hahn et al.	379/265.02
*	J	US-2002/0188584	12-2002	GHANNAM et al.	707/1
*	K	US-6,738,933	05-2004	Fraenkel et al.	714/47
*	L	US-6,526,044	02-2003	Cookmeyer et al.	370/352
*	M	US-2001/0054097	12-2001	Chafe, Steven	709/224

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Adrian Cockcroft, "Observability", SUN Microsystems, Inc., 1999
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.